Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/627,780 Examiner	FAN, KEJUN Art Unit	
Young J. Kim	1637	

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SEARCH NOT (INCLUDING SEARCH)
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	11/7/2006	YJK
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